



March 2015

## FQT13N06L

### N-Channel QFET<sup>®</sup> MOSFET

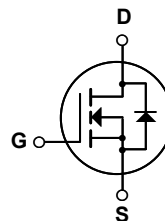
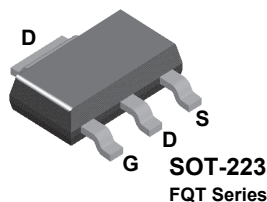
60 V, 2.8 A, 110 mΩ

#### General Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor<sup>®</sup>'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

#### Features

- 2.8 A, 60 V,  $R_{DS(on)} = 110 \text{ m}\Omega$  (Max.) @  $V_{GS} = 10 \text{ V}$ ,  $I_D = 1.4 \text{ A}$
- Low Gate Charge (Typ. 4.8 nC)
- Low  $C_{rss}$  (Typ. 17 pF)
- 100% Avalanche Tested



#### Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	FQT13N06L	Unit
$V_{DSS}$	Drain-Source Voltage	60	V
$I_D$	Drain Current - Continuous ( $T_C = 25^\circ\text{C}$ ) - Continuous ( $T_C = 70^\circ\text{C}$ )	2.8	A
		2.24	A
$I_{DM}$	Drain Current - Pulsed (Note 1)	11.2	A
$V_{GSS}$	Gate-Source Voltage	$\pm 20$	V
$E_{AS}$	Single Pulsed Avalanche Energy (Note 2)	85	mJ
$I_{AR}$	Avalanche Current (Note 1)	2.8	A
$E_{AR}$	Repetitive Avalanche Energy (Note 1)	0.21	mJ
$dv/dt$	Peak Diode Recovery $dv/dt$ (Note 3)	7.0	V/ns
$P_D$	Power Dissipation ( $T_C = 25^\circ\text{C}$ ) - Derate above $25^\circ\text{C}$	2.1	W
		0.017	W/ $^\circ\text{C}$
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
$T_L$	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds	300	$^\circ\text{C}$

#### Thermal Characteristics

Symbol	Parameter	Typ	Max	Unit
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *	--	60	$^\circ\text{C}/\text{W}$

\* When mounted on the minimum pad size recommended (PCB mount).

FQT13N06L — N-Channel QFET<sup>®</sup> MOSFET

**Electrical Characteristics** $T_C = 25^\circ\text{C}$  unless otherwise noted.

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
<b>Off Characteristics</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$	60	--	--	V
$\Delta BV_{DSS} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250\text{ }\mu\text{A}$ , Referenced to $25^\circ\text{C}$	--	0.05	--	V/ $^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 60\text{ V}, V_{GS} = 0\text{ V}$	--	--	1	$\mu\text{A}$
		$V_{DS} = 48\text{ V}, T_C = 125^\circ\text{C}$	--	--	10	$\mu\text{A}$
$I_{GSSF}$	Gate-Body Leakage Current, Forward	$V_{GS} = 20\text{ V}, V_{DS} = 0\text{ V}$	--	--	100	nA
$I_{GSSR}$	Gate-Body Leakage Current, Reverse	$V_{GS} = -20\text{ V}, V_{DS} = 0\text{ V}$	--	--	-100	nA

**On Characteristics**

$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$	1.0	--	2.5	V
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = 10\text{ V}, I_D = 1.4\text{ A}$	--	0.088	0.11	$\Omega$
		$V_{GS} = 5\text{ V}, I_D = 1.4\text{ A}$	--	0.110	0.14	$\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS} = 25\text{ V}, I_D = 1.4\text{ A}$ (Note 4)	--	4.1	--	S

**Dynamic Characteristics**

$C_{iss}$	Input Capacitance	$V_{DS} = 25\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$	--	270	350	pF
$C_{oss}$	Output Capacitance		--	95	125	pF
$C_{rss}$	Reverse Transfer Capacitance		--	17	23	pF

**Switching Characteristics**

$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 30\text{ V}, I_D = 6.8\text{ A},$ $R_G = 25\text{ }\Omega$  (Note 4, 5)	--	8	25	ns
$t_r$	Turn-On Rise Time		--	90	190	ns
$t_{d(off)}$	Turn-Off Delay Time		--	20	50	ns
$t_f$	Turn-Off Fall Time		--	40	90	ns
$Q_g$	Total Gate Charge	$V_{DS} = 48\text{ V}, I_D = 13.6\text{ A},$ $V_{GS} = 5\text{ V}$  (Note 4, 5)	--	4.8	6.4	nC
$Q_{gs}$	Gate-Source Charge		--	1.6	--	nC
$Q_{gd}$	Gate-Drain Charge		--	2.7	--	nC

**Drain-Source Diode Characteristics and Maximum Ratings**

I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current		--	--	2.8	A
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current		--	--	11.2	A
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2.8 A	--	--	1.5	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 13.6 A, dI <sub>F</sub> / dt = 100 A/μs (Note 4)	--	45	--	ns
Q <sub>rr</sub>	Reverse Recovery Charge		--	45	--	nC

**Notes:**

1. Repetitive rating : pulse-width limited by maximum junction temperature.
2.  $L = 12.6\text{ mH}, I_{AS} = 2.8\text{ A}, V_{DD} = 25\text{ V}, R_G = 25\text{ }\Omega$ , starting  $T_J = 25^\circ\text{C}$ .
3.  $I_{SD} \leq 13.6\text{ A}, di/dt \leq 300\text{ A}/\mu\text{s}, V_{DD} \leq BV_{DSS}$ , starting  $T_J = 25^\circ\text{C}$ .
4. Pulse test : pulse width  $\leq 300\text{ }\mu\text{s}$ , Duty cycle  $\leq 2\%$ .
5. Essentially independent of operating temperature.

## Typical Characteristics

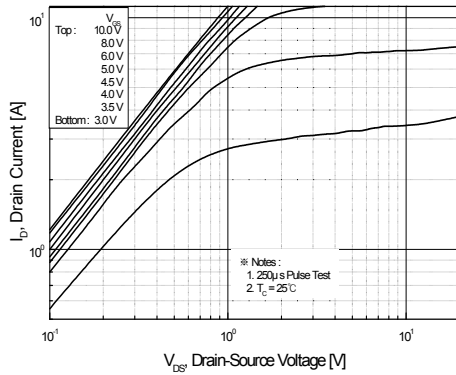


Figure 1. On-Region Characteristics

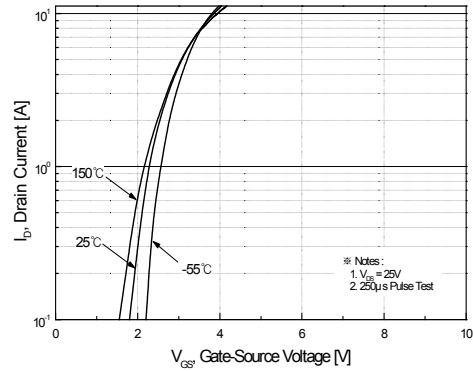


Figure 2. Transfer Characteristics

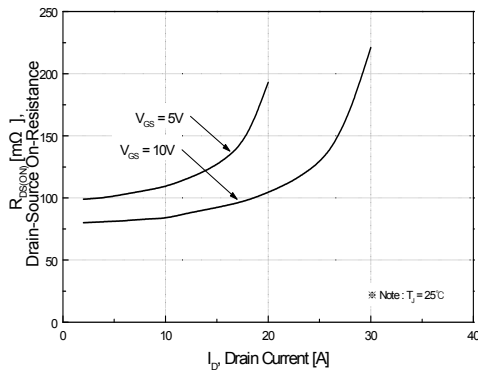


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

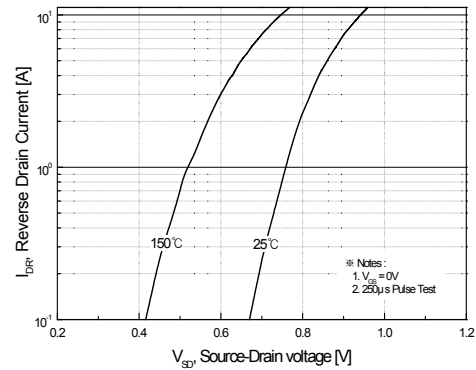


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

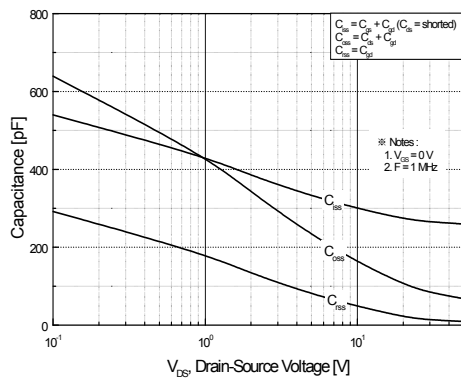


Figure 5. Capacitance Characteristics

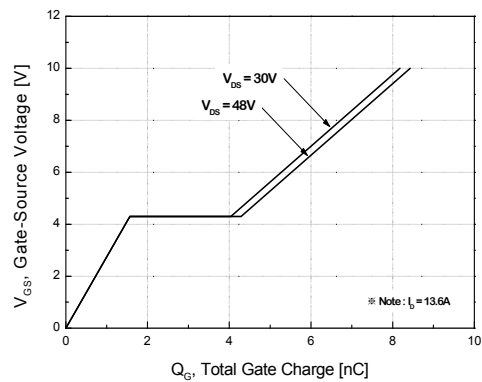
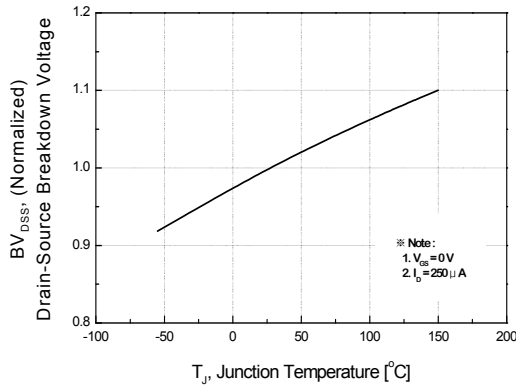
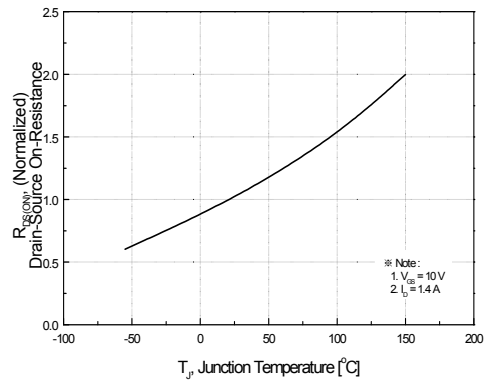


Figure 6. Gate Charge Characteristics

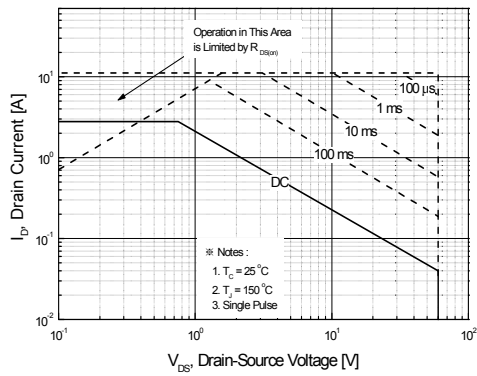
## Typical Characteristics (Continued)



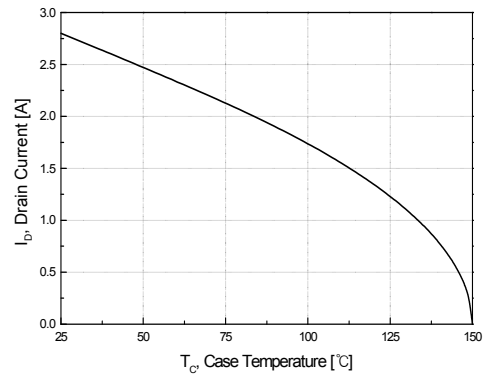
**Figure 7. Breakdown Voltage Variation vs Temperature**



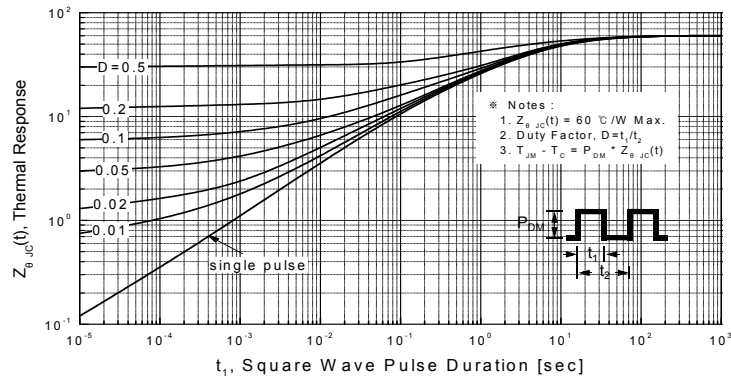
**Figure 8. On-Resistance Variation vs Temperature**



**Figure 9. Maximum Safe Operating Area**



**Figure 10. Maximum Drain Current vs Case Temperature**



**Figure 11. Transient Thermal Response Curve**

Figure 12. Gate Charge Test Circuit & Waveform

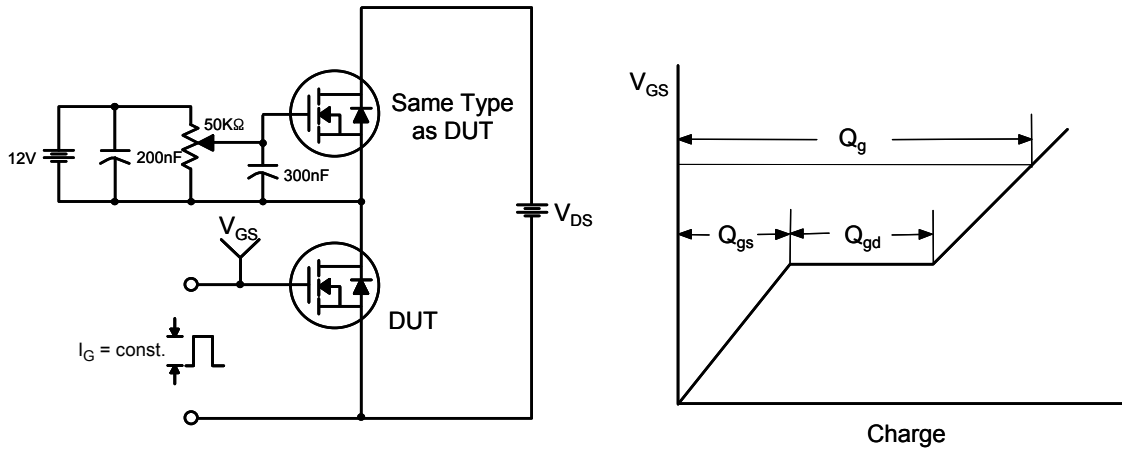


Figure 13. Resistive Switching Test Circuit & Waveforms

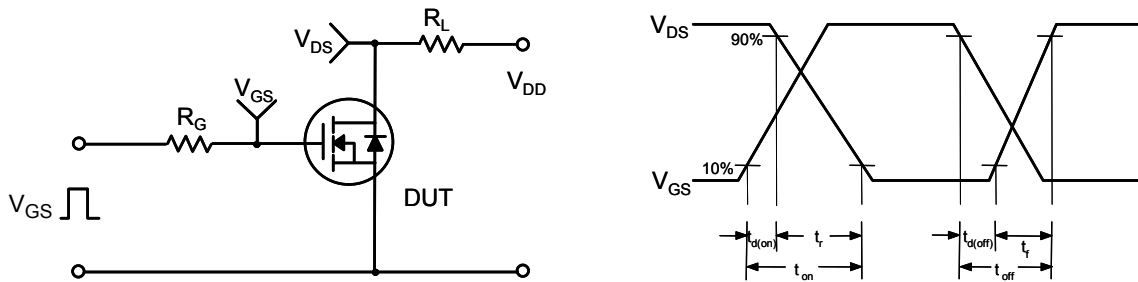
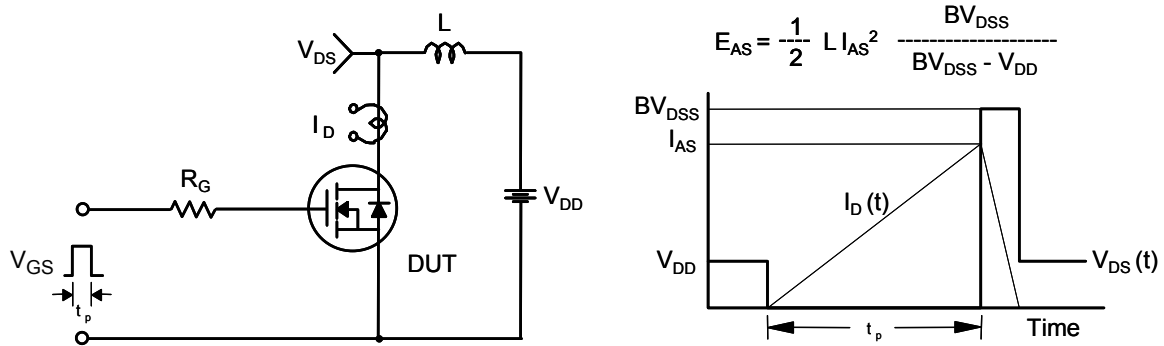


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms



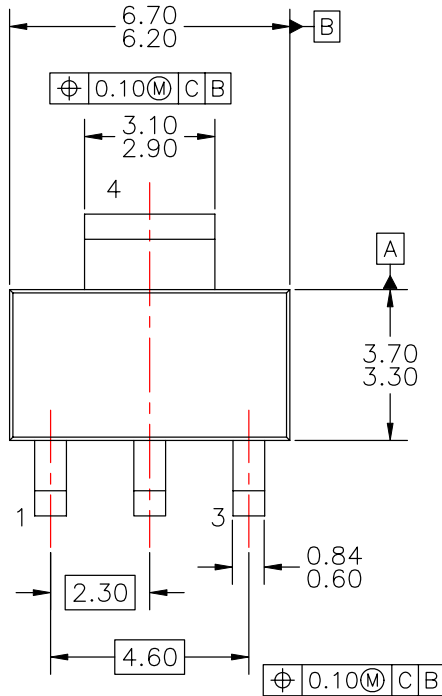
The top diagram shows a circuit for characterizing the body diode of a MOSFET. A MOSFET (DUT) is connected in series with an inductor  $L$  and a DC source  $V_{DD}$ . The MOSFET's gate is driven by a pulse generator  $V_{GS}$  through a resistor  $R_G$ . The MOSFET is labeled "Same Type as DUT". The drain-source voltage is  $V_{DS}$  and the drain-source current is  $I_{SD}$ . The inductor is labeled  $L$ . The DC source is labeled  $V_{DD}$ . The MOSFET is labeled "DUT".

The bottom part of the image shows three waveforms:

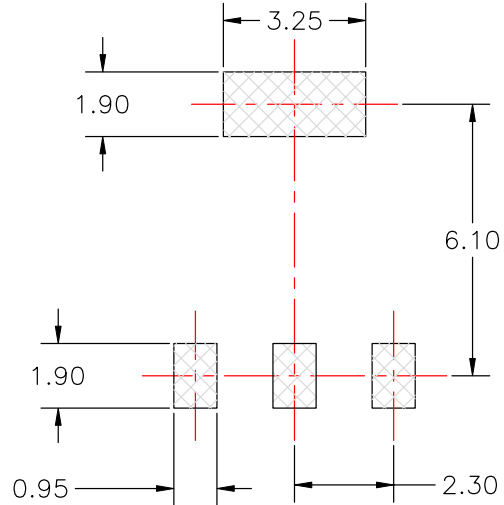
- $V_{GS}$  (Driver):** A square wave pulse. The duty cycle is defined as  $D = \frac{\text{Gate Pulse Width}}{\text{Gate Pulse Period}}$ . The pulse height is  $10V$ .
- $I_{SD}$  (DUT):** The drain-source current. It shows a forward current  $I_{FM}$  (Body Diode Forward Current) during the pulse, followed by a reverse current  $I_{RM}$  (Body Diode Reverse Current) during the recovery phase. The recovery phase is labeled  $di/dt$ .
- $V_{DS}$  (DUT):** The drain-source voltage. It shows a forward voltage drop  $V_{SD}$  (Body Diode Forward Voltage Drop) during the pulse, followed by a recovery voltage  $V_{DD}$  (Body Diode Recovery  $dv/dt$ ) during the recovery phase.

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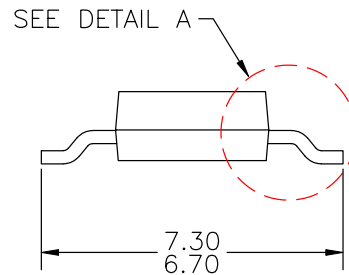
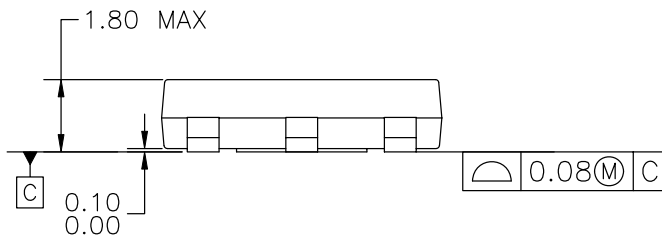
**APPROVED**  
July-14-2008



REVISIONS			
LTR	DESCRIPTION	DATE	NAME/SITE
A	RELEASE TO DOCUMENT CONTROL	JAN.25.1996	TL/FSCP
2	CHG DWG TEMPLATE FR NATIONAL TO FAIRCHILD; CHG DIM STYLE FR DUAL INCH[MM] TO SINGLE, MM; CHG LD WID FR 0.74 $\pm$ 0.05 TO 0.60-0.84; REMOVE PKG THICK DIM (1.6); CHG TOTAL PKG HT FR 1.5 TO 1.80 MAX; CHG FOOT LANDING DIM FR 0.91 MIN TO 0.60 MIN; CHG LD THICKNESS FR 0.35 $\pm$ 0.08 TO 0.20-0.35; ADD DRAFT ANGLE OF MOLDED BODY TOP & BOT; CHG LD LGTH TO PKG EDGE DIM TO BASIC; CHG LD PITCH FR 2.29 BS TO 2.30 BS; CHG BODY WID FR 3.56 $\pm$ 0.38 TO 3.30; CHG BODY LN FR 6.55 $\pm$ 0.38 TO 6.30; CHG TOTAL PKG WID FR 6.94 $\pm$ 0.38 TO 7.30; CHG PAD SIZE FR 0.99 MAX TO 0.95; CHG PAD PITCH FR 2.286 TO 2.30; CHG THERMAL TAB SIZE FR 3.28 MAX TO 3.25; CHG PAD SIZE FR 1.5 TO 1.90; CHG PAD SPACE FR 6.3 TO 6.10; CHG NOTE '2' TO 'A' W/O DATE; DEL NOTE ON LD FINISH; ADD NOTES B, C, D, E & F.	12FEB08	LZSC/FSCP

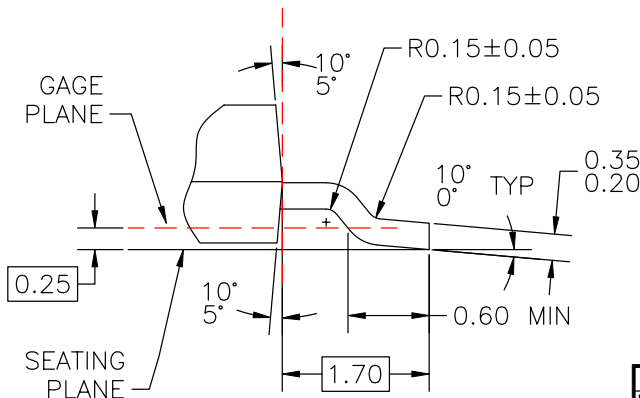


LAND PATTERN RECOMMENDATION





NOTES: UNLESS OTHERWISE SPECIFIED

- A) DRAWING BASED ON JEDEC REGISTRATION TO-261, VARIATION AA.
- B) DIMENSIONS ARE INCLUSIVE OF BURRS, MOLD FLASH AND TIE BAR EXTRUSIONS.
- C) ALL DIMENSIONS ARE IN MILLIMETERS.
- D) DRAWING CONFORMS TO ASME Y14.5M-1994.
- E) LANDPATTERN NAME: SOT230P700X180-4BN
- F) DRAWING FILENAME: MKT-MA04AREV2



**DETAIL A**  
SCALE: 2:1

APPROVALS		DATE			
DRAWN:	J.U. COMPARATIVO JR.	26FEB2008			
CHECKED:	L.Z. STA CRUZ	<div><div>FAIRCHILD</div><div>SEMICONDUCTOR™</div></div> <div>MOLDED PACKAGE</div> <div>SOT-223, 4 LEAD</div>			
APPROVED:	M.R. GESTOLE				
G.S. BAJE					
PROJECTION					
		SCALE 1:1	SIZE A3	DRAWING NUMBER MKT-MA04A	REV 2
INCH		FORMERLY: N/A		SHEET : 1 OF 1	



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Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

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